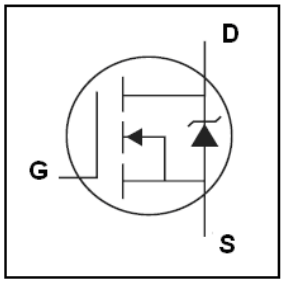
Features

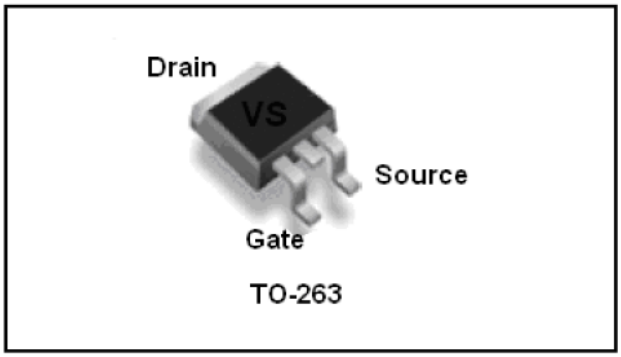
- Low On-Resistance
- Fast Switching
- 100% Avalanche Tested
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant



V_{DSS}	80V
$R_{DS(on)}$	9mΩ
I_D	66A

Description

VS8066ATD designed by the trench processing techniques to achieve extremely low on-resistance. fast switching speed and improved repetitive avalanche rating . These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.



Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only;and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter		Rating	Unit
Common Ratings (Tc=25°C Unless Otherwise Noted)				
V_{GS}	Gate-Source Voltage		±20	V
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage		80	V
T_J	Maximum Junction Temperature		150	°C
T_{STG}	Storage TemperatureRange		-55 to 150	°C
I_S	Diode Continuous Forward Current	T_C =25°C	60	A
Mounted on Large Heat Sink				
I_{DM}	Pulse Drain Current Tested ①	T_C =25°C	260	A
I_D	Continuous Drain current@VGS=10V	T_C =25°C	66	A
P_D	Maximum Power Dissipation	T_C =25°C	130	W
$R_{\theta JC}$	Thermal Resistance-Junction to Case		0.96	°C/W
$R_{\theta JA}$	Thermal Resistance Junction-Ambient		62.5	°C/W
Drain-Source Avalanche Ratings				
EAS	Avalanche Energy, Single Pulsed ②		225	mJ

Symbol	Parameter	Condition	Min.	Typ.	Max.	Unit
Static Electrical Characteristics @ T_J = 25°C (unless otherwise stated)						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	V_{GS}=0V I_D=250μA	80	--	--	V
I_{DSS}	Zero Gate Voltage Drain Current(Tc=25℃)	V_{DS}=80V,V_{GS}=0V	--	--	1	μA
	Zero Gate Voltage Drain Current(Tc=125℃)		--	--	100	μA
I_{GSS}	Gate-Body Leakage Current	V_{GS}=±20V,V_{DS}=0V	--	--	±100	nA
$V_{GS(TH)}$	Gate Threshold Voltage	V_{DS}=V_{GS},I_D=250μA	2	3	4	V
$R_{DS(ON)}$	Drain-Source On-State Resistance③	V_{GS}=10V, I_D=40A	--	9	11	mΩ
Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise stated)						
C_{iss}	Input Capacitance	V_{DS}=40V,V_{GS}=0V, f=1MHz	--	2780	--	pF
C_{oss}	Output Capacitance		--	295	--	pF
C_{rss}	Reverse Transfer Capacitance		--	175	--	pF
Q_g	Total Gate Charge	V_{DS}=40V,I_D=30A, V_{GS}=10V	--	55	--	nC
Q_{gs}	Gate-Source Charge		--	14	--	nC
Q_{gd}	Gate-Drain Charge		--	16	--	nC
Switching Characteristics						
$t_{d(on)}$	Turn-on Delay Time	V_{DD}=40V, I_D=1A, R_G=6.8Ω, V_{GS}=10V	--	13.6	--	nS
t_r	Turn-on Rise Time		--	10	--	nS
$t_{d(off)}$	Turn-Off Delay Time		--	48	--	nS
t_f	Turn-Off Fall Time		--	20	--	nS
Source- Drain Diode Characteristics@ T_J = 25°C (unless otherwise stated)						
I_{SD}	Source-drain current(Body Diode)	T_C=25℃	--	--	66	A
V_{SD}	Forward on voltage	I_{SD}=30A,V_{GS}=0V	--	0.85	1.3	V
t_{rr}	Reverse Recovery Time	T_j=25℃,I_{sd}=30A, V_{GS}=0V di/dt=100A/μs	--	43	--	nS
Q_{rr}	Reverse Recovery Charge		--	62	--	nC

NOTE:

Repetitive rating; pulse width limited by max. junction temperature.

Limited by T_{Jmax}, starting T_J = 25°C, L = 0.5mH,R_G = 25Ω, I_{AS} = 30A, V_{GS} =10V. Part not recommended for use above this value

Pulse width ≤ 300μs; duty cycle≤ 2%.

Typical Characteristics

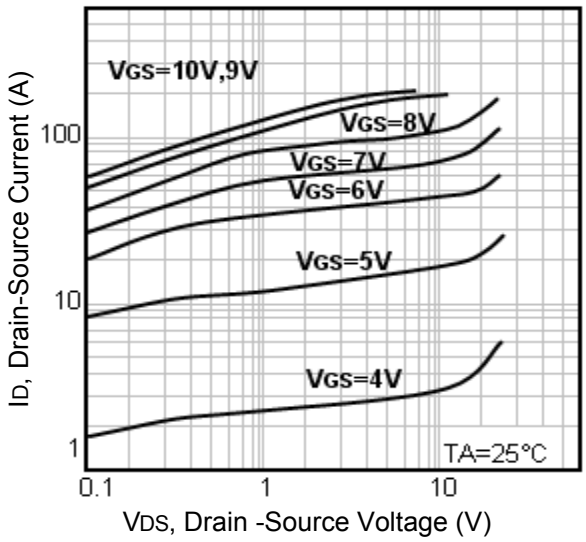


Fig1. Typical Output Characteristics

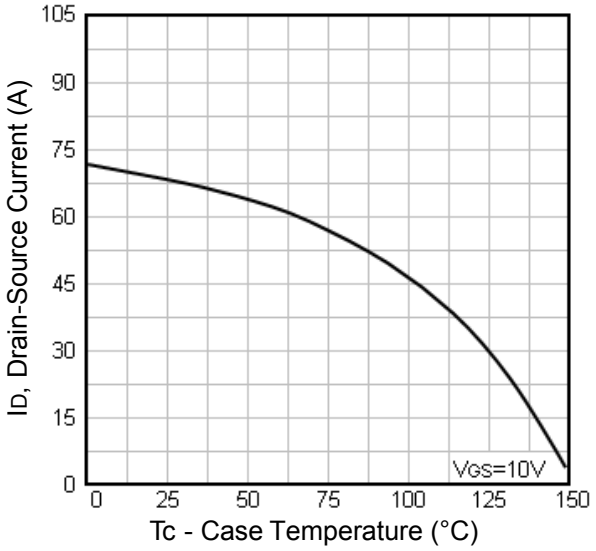


Fig2. Maximum Drain Current Vs.Case Temperature

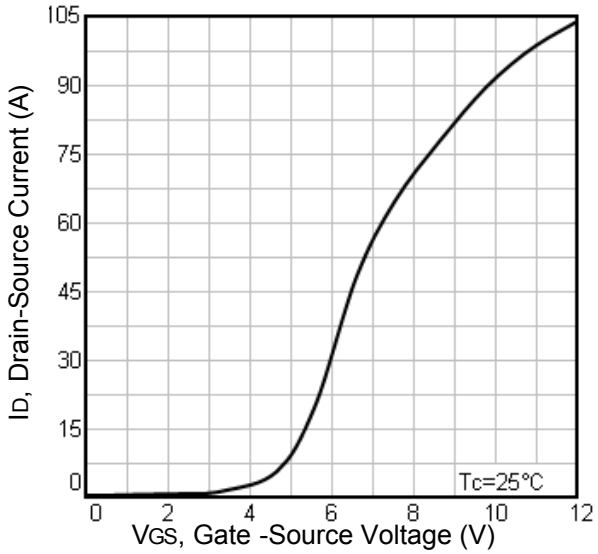


Fig3. Typical Transfer Characteristics

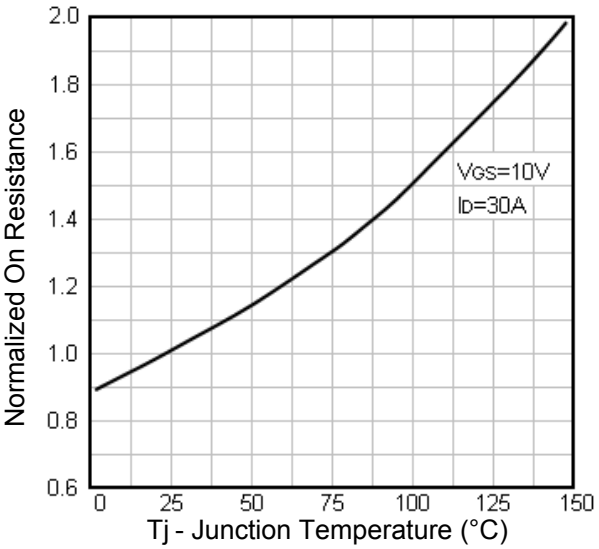


Fig4. Normalized On-Resistance Vs. Temperature

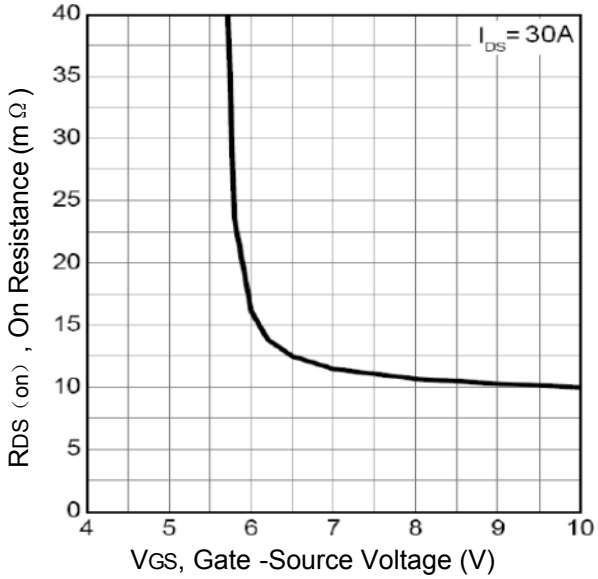


Fig5.Typical VGS Vs. On Resistance

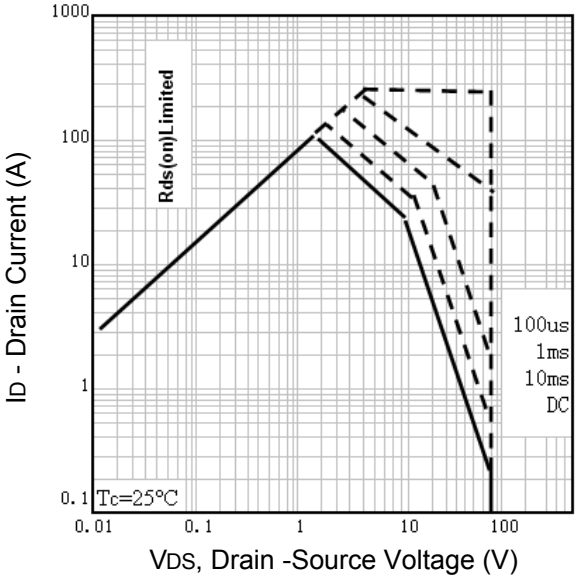


Fig6. Maximum Safe Operating Area

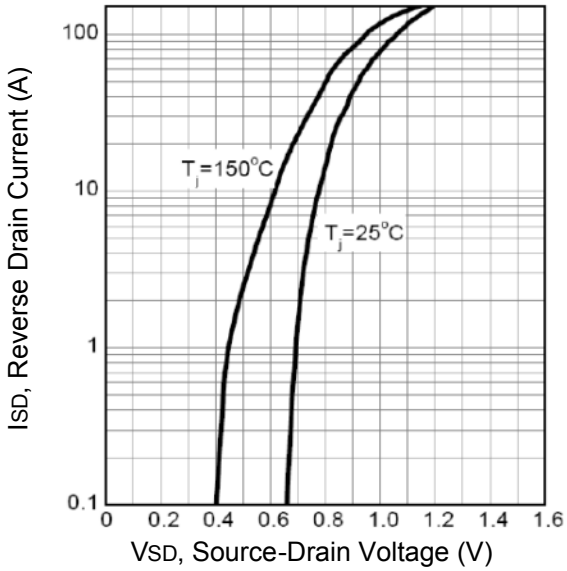


Fig7. Typical Source-Drain Diode Forward Voltage

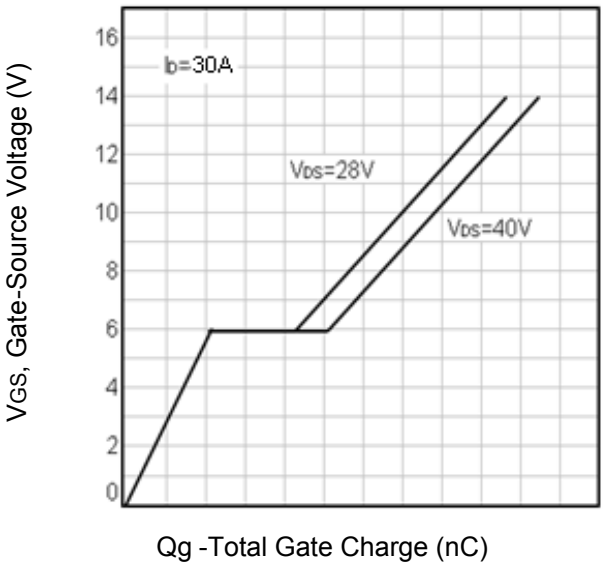


Fig8. Typical Gate Charge Vs.Gate-Source Voltage

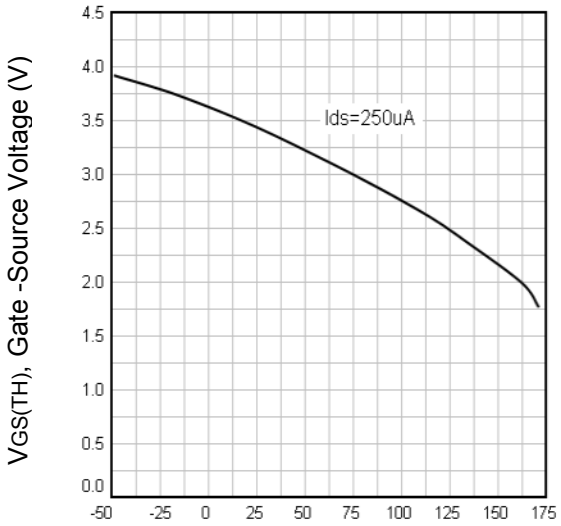


Fig9. Threshold Voltage Vs. Temperature

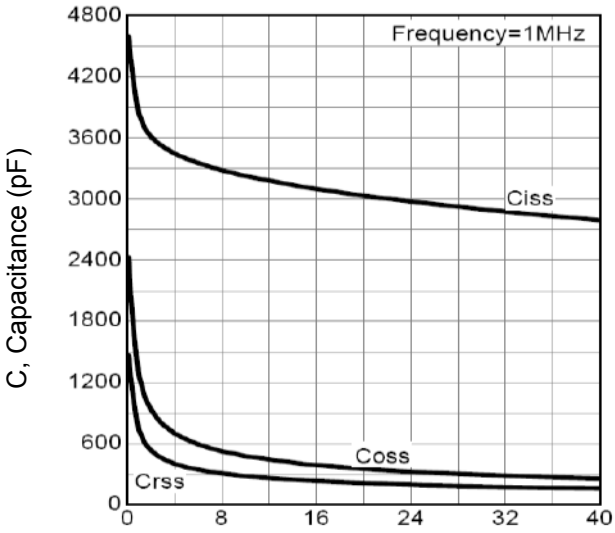


Fig10. Typical Capacitance Vs.Drain-Source Voltage

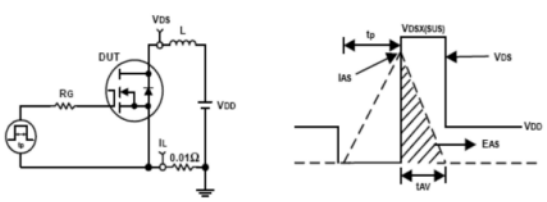


Fig11. Unclamped Inductive Test Circuit and waveforms

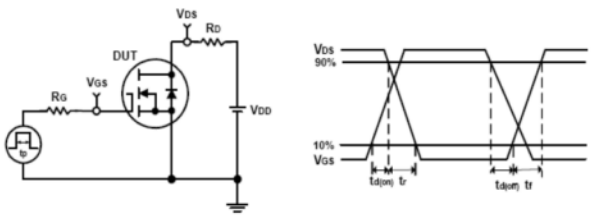
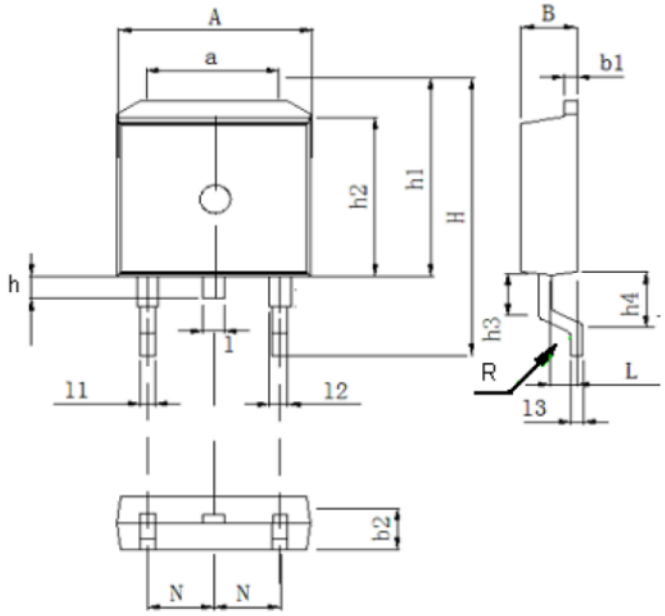


Fig12. Switching Time Test Circuit and waveforms

TO-263 Package Outline



DIM	MILLIMETERS
A	9.8±0.2
a	7.4±0.2
B	4.5±0.2
b1	1.3±0.05
b2	2.4±0.2
H	15.5±0.3
h	1.54±0.2
h1	10.5±0.2
h2	9.2±0.1
h3	1.54±0.2
h4	2.7±0.2
L	2.4±0.2
l	1.3±0.1
l1	0.8±0.1
l2	1.3±0.1
l3	0.5±0.1
N	2.45

Order Information

Product	Marking	Package	Packaging	Min Unit Quantity
VS8066ATD	VS8066ATD	TO-263	800PCS/Reel	1600PCS

Customer Service

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